Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/090,424	JORMANAINEN ET AL.	
Examiner	Art Unit	
Binh Q. Nguyen	2664	

SEARCHED				
Class	Subclass	Date	Examiner	
370	395.1	11/4/2005	BQN	
370	395.64	11/4/2005	BQN	
370	395.5	11/4/2005	BQN	
370	229	11/4/2005	BQN	
370	230	11/4/2005	BQN	
370	230.1	11/4/2005	BQN	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	11/4/2005	BQN
Consulted with Wellington Chin	11/03/2005	BQN
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